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**1 An embedded autonomous scan-based results analyzer (EARA) for SoC cores**

*Nahvi, M.; Ivanov, A.;*

VLSI Test Symposium, 2003. Proceedings. 21st , 27 April-1 May 2003

Pages:293 - 298

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**2 Non-intrusive built-in self-test for FPGA and MCM applications**

*Russ, A.D.; Stroud, C.E.;*

AUTOTESTCON '95. 'Systems Readiness: Test Technology for the 21st Century'. Conference Record , 8-10 Aug. 1995

Pages:480 - 485

[\[Abstract\]](#)   [\[PDF Full-Text \(608 KB\)\]](#)   **IEEE CNF**